

CONTENTS

1. Elementary Crystallography	1
1-1 THE CRYSTALLINE STATE	1
1-1.1 Crystalline and Amorphous Solids,	1
1-1.2 Definition of a Crystal,	3
1-1.3 Characteristics of the Crystalline and Vitreous States,	3
1-2 CRYSTAL GEOMETRY	4
1-2.1 External Form and Habit of Crystals,	4
1-2.2 Constancy of Interfacial Angles,	6
1-2.3 Symmetry Elements of Crystals,	6
1-2.4 Pseudosymmetry,	13
1-2.5 Crystallographic Axes,	13
1-2.6 Axial Ratios,	14
1-2.7 The Six Crystal Symmetry Systems,	14
1-2.8 Miller Indices,	16
1-2.9 The Law of Rational Indices,	18
1-2.10 Crystal Forms,	19
1-2.11 Composite Crystals and Twinning,	22
1-2.12 Equation for the Plane (<i>hkl</i>),	24
1-2.13 Zones and Zone Relationships,	26
1-3 SPACE LATTICES	28
1-3.1 Historical Introduction,	28
1-3.2 Definition,	30
1-3.3 The Unit Cell,	31
1-3.4 The 14 Bravais Lattices,	31
1-3.5 Some Crystallographic Implications of Space Lattices,	34
1-3.6 Distance between Neighboring Lattice Planes in the Series (<i>hkl</i>),	35
1-3.7 The Reciprocal Lattice,	38
1-4 POINT GROUPS AND SPACE GROUPS	41
1-4.1 The Point Group or Crystal Symmetry Class,	41
1-4.2 The Space Group,	49
GENERAL REFERENCES	55
SPECIFIC REFERENCES	56

2. The Production and Properties of X-rays	58
2-1 X-RAY SAFETY AND PROTECTION	58
2-2 THE PRODUCTION OF X-RAYS	60
2-2.1 The Origin of X-rays,	60
2-2.2 X-ray Tubes,	61
<i>A. Gas tubes,</i>	61
<i>B. Hot-cathode tubes,</i>	62
<i>C. Modern diffraction tube design,</i>	64
<i>D. Cold-cathode diffraction tubes,</i>	67
<i>E. High-intensity diffraction tubes,</i>	70
<i>F. Microfocus diffraction tubes,</i>	71
2-2.3 Power Equipment for the Production of X-rays,	73
2-2.4 Commercial X-ray Generators for Diffraction,	77
2-2.5 Isotopic X-ray Sources,	79
2-3 PROPERTIES OF X-RAYS AND THEIR MEASUREMENT	80
2-3.1 The X-ray Spectrum of an Element,	80
<i>A. The continuous x-ray spectrum,</i>	82
<i>B. The characteristic x-ray spectrum,</i>	84
2-3.2 The Precise Determination of X-ray Wavelengths,	90
2-3.3 Absorption of X-rays,	94
2-3.4 Secondary Fluorescent and Scattered X-rays,	97
2-3.5 Refraction of X-rays,	100
2-3.6 Monochromatization of X-radiation,	102
<i>A. Single filter technique,</i>	102
<i>B. Balanced-filter technique,</i>	105
<i>C. Crystal monochromator techniques,</i>	107
<i>D. Graphite monochromators,</i>	113
2-3.7 The Photographic Effects of X-rays,	114
GENERAL REFERENCES	116
SPECIFIC REFERENCES	117
3. Fundamental Principles of X-ray Diffraction	120
3-1 KINEMATICAL AND DYNAMICAL DIFFRACTION THEORY	120
3-2 THE GEOMETRY OF DIFFRACTION	121
3-2.1 Scattering of X-rays by Electrons and Atoms,	121
3-2.2 Scattering by a Regularly Spaced Row of Atoms,	122

3-2.3	Conditions for Diffraction by a Linear Lattice of Atoms,	123
3-2.4	Diffraction by a Simple Cubic Lattice,	126
3-2.5	Proof that the "Diffracting Plane" is a Lattice Plane,	129
3-2.6	The Bragg Equation,	130
3-2.7	Derivation of the Bragg Equation from the "Reflection" Analogy,	130
3-2.8	The Geometrical Picture of Diffraction in Reciprocal Space,	132
3-3	THE INTENSITY OF DIFFRACTION	135
3-3.1	Perfect and Imperfect Crystals,	135
3-3.2	Primary and Secondary Extinction,	139
3-3.3	Relative and Absolute Intensities,	140
3-3.4	Factors Affecting the Diffraction Intensities,	142
	<i>A. The polarization factor,</i>	142
	<i>B. The Lorentz and "velocity" factors,</i>	143
	<i>C. The temperature factor,</i>	144
	<i>D. The atomic scattering factor,</i>	148
	<i>E. The structure factor,</i>	152
	<i>F. The multiplicity factor,</i>	162
	<i>G. The absorption factor,</i>	163
3-3.5	Expressions for the Relative Intensity of Diffraction by the Various Techniques,	167
3-3.6	Lattice-Centering and Space-Group Extinctions,	167
	GENERAL REFERENCES	171
	SPECIFIC REFERENCES	172
4.	Photographic Powder Techniques	175
4-1	THE DEBYE-SCHERRER METHOD	177
4-1.1	Introduction,	177
4-1.2	Camera Design,	179
	<i>A. General geometry,</i>	179
	<i>B. Details of camera construction,</i>	186
	<i>C. Camera support and alignment,</i>	195
4-1.3	Preparation of the Powder,	202
4-1.4	Mounting the Powder,	206
4-1.5	Making the Exposure,	216
4-1.6	Processing the Film,	222
4-2	PARAFOCUSING METHODS	222

4-3	MONOCHROMATIC-PINHOLE TECHNIQUES	232
4-3.1	Forward-Reflection Method,	232
4-3.2	Back-Reflection Method,	235
4-4	MICROCAMERAS AND MICROBEAM TECHNIQUES	240
4-5	HIGH-TEMPERATURE TECHNIQUES	245
4-6	LOW-TEMPERATURE TECHNIQUES	254
4-7	HIGH-PRESSURE TECHNIQUES	259
	GENERAL REFERENCES	266
	SPECIFIC REFERENCES	266
5.	Diffractometric Powder Technique	271
5-1	GEOMETRY OF THE POWDER DIFFRACTOMETER	272
5-1.1	General Features,	272
5-1.2	Details of the Optical Arrangement,	274
5-1.3	The Seemann-Bohlin Diffractometer,	280
5-1.4	Alignment and Angular Calibration of the Diffractometer,	280
	<i>A. Operations appropriately performed in advance by the manufacturer,</i>	281
	<i>B. Further internal alignment of the goniometer,</i>	281
	<i>C. Alignment of the goniometer with respect to the x-ray tube,</i>	282
	<i>D. Calibration of the $0^\circ 2\theta$ position,</i>	285
	<i>E. Calibration of angular registration between 0 and $180^\circ 2\theta$,</i>	287
5-2	PROFILES AND POSITIONS OF DIFFRACTION MAXIMA	290
5-2.1	Convolution Synthesis of Line Profiles,	290
	<i>A. X-ray source, g_I,</i>	291
	<i>B. Flat specimen surface, g_{II},</i>	291
	<i>C. Axial divergence, g_{III},</i>	293
	<i>D. Specimen transparency, g_{IV},</i>	294
	<i>E. Receiving slit, g_V,</i>	295
	<i>F. Comparison of calculated and experimental line profiles,</i>	295
5-2.2	Displacement and Breadth of Diffraction Maxima,	297
	<i>A. Line position,</i>	298
	<i>B. Line breadth,</i>	299
	<i>C. The practical determination of the centroid and variance,</i>	300

5-2.3	Accurate Determination of Interplanar (d) Spacings,	306
5-2.4	"Routine" Determination of Interplanar (d) Spacings,	308
5-3	ELECTRICAL CHARACTERISTICS OF THE DIFFRACTOMETER	311
5-3.1	General Arrangement of Components,	311
5-3.2	Radiation Detectors (Quantum Counters),	313
	<i>A. Gas-ionization counters,</i>	314
	<i>B. Geiger-Müller counters,</i>	316
	<i>C. Proportional counters,</i>	322
	<i>D. Scintillation counters,</i>	327
	<i>E. Solid-state (energy-dispersive) detectors,</i>	330
5-3.3	Nonlinearity of Detector Response,	335
5-3.4	Monochromatizing Techniques,	344
	<i>A. Pulse-height discrimination and analysis,</i>	344
	<i>B. Ross balanced filters,</i>	348
	<i>C. Crystal monochromators,</i>	354
5-4	CHOICE OF EXPERIMENTAL CONDITIONS AND PROCEDURES	358
5-4.1	Statistical Accuracy of Counter Measurements,	360
5-4.2	The Specimen,	364
	<i>A. Preparation of powders,</i>	365
	<i>B. Rotation of the specimen,</i>	368
	<i>C. Preferred orientation and the specimen mount,</i>	368
	<i>D. High-temperature techniques,</i>	376
	<i>E. Low-temperature techniques,</i>	381
	<i>F. Other special specimen techniques,</i>	387
5-4.3	Transmission Techniques,	389
5-4.4	Continuous-Scan Techniques,	391
5-4.5	Step-Scan Techniques and Automation,	403
	GENERAL REFERENCES	412
	SPECIFIC REFERENCES	412
6.	The Interpretation of Powder Diffraction Data	419
6-1	THE VIEWING AND PRECISION MEASUREMENT OF POWDER PHOTOGRAPHS	420
6-2	DETERMINATION OF INTERPLANAR (d) SPACINGS	424
6-2.1	Debye-Scherrer Patterns,	424
6-2.2	Monochromatic-Pinhole (Flat-Film) Patterns,	435

6-3	INDEXING CUBIC POWDER PATTERNS	437
6-3.1	Reciprocal-Lattice Picture of Diffraction by a Cubic Powder,	437
6-3.2	Indexing a Cubic Pattern by $\sin^2 \theta$ Ratios,	439
6-3.3	Determination of the Unit-Cell Dimension a ,	441
6-3.4	Indexing a Cubic Pattern When a Is Known,	443
6-4	DETERMINATION OF LATTICE TYPE	445
6-5	INDEXING NONCUBIC POWDER PATTERNS	446
6-5.1	Indexing Noncubic Patterns When the Unit-Cell Dimensions are Known,	446
6-5.2	Graphical Methods of Indexing,	447
6-5.3	Analytical Methods of Indexing: Tetragonal, Hexagonal, and Orthorhombic Patterns,	451
6-5.4	Analytical Methods of Indexing: Monoclinic and Triclinic Patterns,	461
6-6	AUTOMATED COMPUTING PROCEDURES FOR INDEXING POWDER PATTERNS	465
6-6.1	Programs for Patterns of Orthorhombic and Higher Symmetry,	466
6-6.2	Programs for Patterns of Low Symmetry,	467
6-7	THE MEASUREMENT OF INTENSITIES FROM PHOTOGRAPHIC BLACKENING	472
6-7.1	Introduction,	472
6-7.2	Preparation of a Graded Intensity Scale,	473
6-7.3	Visual Estimation of Intensities,	475
6-7.4	Photometer Techniques,	477
6-8	THE MEASUREMENT OF INTENSITIES WITH THE X-RAY DIFFRACTOMETER	486
6-9	PUTTING INTENSITIES ON AN ABSOLUTE SCALE	488
6-10	SPECIAL SCATTERING AND DIFFRACTION EFFECTS	489
6-10.1	Background Effects,	489
	<i>A. Background due to lattice imperfections,</i>	489
	<i>B. Background due to general radiation,</i>	491
	<i>C. Absorption discontinuities,</i>	491
	<i>D. Air scatter,</i>	493
	<i>E. Secondary fluorescence radiation,</i>	493
6-10.2	Reflections of Unusual Character,	494
	<i>A. Spotty lines,</i>	494
	<i>B. Arclike lines,</i>	494

- C. *Broadened lines*, 495
- D. *Two-dimensional lattice lines*, 495
- E. *Splitting of lines*, 497

6-10.3 Spurious lines, 498

- A. *Lines due to misalignment of camera elements*, 498
- B. *Diffraction effects from the sample mount*, 498
- C. *Diffraction from radiation contaminants*, 499

GENERAL REFERENCES 500

SPECIFIC REFERENCES 500

7. Qualitative and Quantitative Analysis of Crystalline Powders 505

7-1 ROUTINE QUALITATIVE IDENTIFICATION OF CRYSTALLINE POWDERS 505

- 7-1.1 The JCPDS Powder Diffraction File (PDF), 506
- 7-1.2 Experimental Technique of the PDF Method, 512
 - A. *Preparation of the diffraction pattern*, 512
 - B. *Measurement of lines on films and diffractometer charts*, 513
 - C. *Identification interpretation of the data*, 514
- 7-1.3 Computer Applications in the PDF Method, 520
- 7-1.4 Complications and Limitations of the PDF Method, 523
- 7-1.5 Special Identification Techniques, 526
 - A. *Compound identification by isomorphism*, 526
 - B. *Procedures for organic compounds*, 527
 - C. *Identification of clay minerals*, 529

7-2 QUANTITATIVE ANALYSIS OF POWDER MIXTURES 531

- 7-2.1 Basic Aspects of Absorption in Quantitative Analysis, 532
 - A. *Mixtures of N components: $\mu_j^* = \bar{\mu}^*$* , 534
 - B. *Mixtures of two components: $\mu_1^* \neq \mu_2^*$* , 536
 - C. *Mixtures of N components: (N > 2); $\mu_1^* \neq \mu_N^*$* , 536
- 7-2.2 Photographic-Microphotometric Technique, 538
- 7-2.3 Counter Diffractometric Technique, 539
 - A. *Instrumental requirements*, 539
 - B. *General recommendations on procedure*, 540
- 7-2.4 Outline of Important Analytical Procedures, 544
 - A. *Direct analysis when $\mu_j^* = \bar{\mu}^*$* , 544
 - B. *Direct analysis of two-component systems, $\mu_1^* \neq \mu_2^*$* , 544

C.	<i>Direct analysis by absorption-diffraction, multicomponent systems,</i>	545
D.	<i>Internal-standard analysis for one component of a multicomponent system, no interfering lines,</i>	549
E.	<i>Internal-standard analysis for one component, interfering lines of unknown and standard,</i>	550
F.	<i>Simultaneous analysis for several components with allowance for line superpositions,</i>	552
G.	<i>Analysis by dilution of sample with y_1 grams of unknown per gram of sample,</i>	553
7-2.5	Selected Examples and Applications,	554
A.	<i>Dust analysis,</i>	554
B.	<i>Retained austenite in steel,</i>	557
C.	<i>Organic mixtures,</i>	558
D.	<i>Miscellaneous inorganic analyses,</i>	561
E.	<i>Analysis of solid-solution phases,</i>	562
GENERAL REFERENCES		562
SPECIFIC REFERENCES		563
8.	The Precision Determination of Lattice Constants	566
8-1	GENERAL CONSIDERATIONS	567
8-2	SOURCES OF SYSTEMATIC ERRORS IN THE DEBYE-SCHERRER METHOD	569
8-2.1	Radius Errors and Film Shrinkage,	569
8-2.2	Specimen Eccentricity,	571
8-2.3	Sample Absorption and Radial Divergence of the Beam,	573
A.	<i>Bradley and Jay's approximate treatment,</i>	574
B.	<i>More rigorous investigations of the absorption error,</i>	577
8-2.4	Axial Divergence of the Beam,	579
8-3	METHODS OF CORRECTING FOR ERRORS IN THE DEBYE-SCHERRER METHOD	581
8-3.1	Use of Calibrating Substances,	581
8-3.2	The Straumanis Method of Refined Experimental Technique,	582
A.	<i>Essential features of the Straumanis method,</i>	582
B.	<i>Illustrative film measurements and calculations,</i>	584

8-3.3	The Convolution-Film Method with the Likelihood Ratio Method,	586
	<i>A. The Convolution-Film Method (CFM),</i>	586
	<i>B. The Likelihood Ratio Method (LRM),</i>	587
	<i>C. Application of the Convolution-Film Method to IUCr Silicon,</i>	589
8-3.4	Use of Extrapolation Methods,	591
	<i>A. Bradley and Jay's extrapolation against $\cos^2 \theta$,</i>	591
	<i>B. Extrapolation against $(\cos^2 \theta)/\sin \theta + (\cos^2 \theta)/\theta$,</i>	594
	<i>C. Cohen's least-squares extrapolation,</i>	597
8-4	PRECISE LATTICE CONSTANTS BY OTHER FILM TECHNIQUES	604
8-5	PRECISE LATTICE CONSTANTS FROM DIFFRACTOMETRIC MEASUREMENTS	606
8-6	THE PRECISION DETERMINATION OF LATTICE CONSTANTS OF NONCUBIC MATERIALS	609
8-7	SUMMARY	612
	GENERAL REFERENCES	615
	SPECIFIC REFERENCES	615
9.	Crystallite Size and Lattice Strains From Line Broadening	618
9-1	DETERMINATION OF THE PURE LINE PROFILE	619
9-1.1	The Fourier-Transform Method,	619
	<i>The Rachinger Correction,</i>	625
9-1.2	The Method of Iterative Folding,	628
9-1.3	Simplified Methods,	634
	<i>A. Gaussian or Cauchy profiles,</i>	635
	<i>B. Jones' correction curves for Debye-Scherrer lines,</i>	635
	<i>C. The $K\alpha_1\alpha_2$ doublet correction for the Debye-Scherrer technique,</i>	637
	<i>D. Correction curves for diffractometer line profiles,</i>	640
9-2	DETERMINATION OF CRYSTALLITE SIZE AND LATTICE IMPERFECTIONS SIMULTANEOUSLY	642
9-2.1	Introduction,	642
9-2.2	The Fourier Method of Warren and Averbach,	643
	<i>A. Derivation of the Fourier series expression,</i>	644
	<i>B. Separation of size and distortion components,</i>	649
	<i>C. Generalization of the Warren-Averbach theory,</i>	652

9-2.3	Use of Variance of the Line Profile,	655
	<i>A. Contribution of crystallite size to the variance,</i>	657
	<i>B. Contribution of lattice distortions to the variance,</i>	660
9-2.4	Method of Integral Breadths,	661
9-2.5	Determination of Faulting in Layered Structures,	665
	<i>A. Deformation and twin faulting,</i>	666
	<i>B. Random-layer (turbostratic) structures,</i>	667
9-2.6	Very Defective Lattices,	668
9-2.7	Illustrative Analyses,	671
	<i>A. Cold-worked copper-silicon single crystal, Fourier method,</i>	671
	<i>B. Deformed thoriated tungsten, variance method,</i>	672
	<i>C. Deformed cubic metals, Fourier and integral-breadth methods, compound fault probability evaluated,</i>	675
	<i>D. Comparison of size and strain values derived by four methods,</i>	682
	<i>E. Additional literature,</i>	683
9-3	DETERMINATION OF CRYSTALLITE SIZE—NO LATTICE IMPERFECTIONS	687
9-3.1	The Scherrer Equation,	687
	<i>Crystallites of markedly anisotropic shapes,</i>	690
9-3.2	The Variance Method,	692
9-3.3	Size Distributions,	692
9-3.4	Some Practical Considerations,	694
9-3.5	Illustrative Analyses,	696
	<i>A. Crystallite shape—Magnesium Oxide (MgO) powder,</i>	696
	<i>B. MgO from decomposition of MgCO_3 at 600°C,</i>	698
	<i>C. MgO from decomposition of MgCO_3 at 900°C,</i>	699
	<i>D. Micronized quartzite powder, fraction $< 5\mu$,</i>	700
	<i>E. L_c dimension of a carbon black,</i>	700
	<i>F. L_a dimension of a carbon black,</i>	703
	GENERAL REFERENCES	704
	SPECIFIC REFERENCES	705
10.	Investigation of Preferred Orientation and Texture	709
10-1	ORIENTATION AND TEXTURE IN MATERIALS	709
10-2	GEOMETRY OF FIBER PATTERNS	713
10-2.1	Ideal Fiber Patterns,	713

10-2.2 Bragg Geometry of Fiber Patterns,	717
10-2.3 Real Fiber Patterns,	719
10-3 PREPARATION OF FIBER PATTERNS	719
10-4 ANALYSIS OF SIMPLE FIBER PATTERNS	723
10-5 REPRESENTATION OF PREFERRED ORIENTATION	725
10-5.1 Pole Figures,	725
10-5.2 The Stereographic Projection,	726
10-5.3 Inverse Pole Figures,	731
10-6 PREPARATION OF POLE FIGURES,	731
10-6.1 Photographic Methods,	731
10-6.2 Diffractometric Techniques,	733
<i>A. Introduction,</i>	733
<i>B. Transmission technique; sheet specimen,</i>	735
<i>C. Reflection technique; sheet specimen,</i>	739
<i>D. Special instrumentation,</i>	741
<i>E. The specimen and its alignment,</i>	747
10-7 MISCELLANEOUS	750
GENERAL REFERENCES	751
SPECIFIC REFERENCES	752
11. Stress Measurement in Metals	755
11-1 ADVANTAGES AND DISADVANTAGES OF DIFFRACTION METHODS	756
11-2 ELASTIC STRESS-STRAIN RELATIONSHIPS	757
11-3 SUM OF THE PRINCIPAL STRESSES IN A SURFACE	760
11-4 COMPONENT OF STRESS IN ANY DESIRED DIRECTION IN A SURFACE	762
11-4.1 Photographic Techniques,	764
<i>A. Double-exposure technique (DET),</i>	766
<i>B. Single-exposure technique (SET),</i>	768
<i>C. General considerations,</i>	769
11-4.2 Diffractometric Techniques,	770
11-4.3 Selected Investigations,	777
<i>A. Hardened steel: comparison of x-ray and mechanical stress measurements,</i>	777
<i>B. Aluminum alloy 2024 and ingot iron: determination of elastic constants,</i>	778

C. <i>High-strength aluminum alloys: residual stress measurements,</i>	781
D. <i>Measurement of a triaxial residual stress,</i>	784
E. <i>Other experimental work and information,</i>	786
11-5 PROBLEMS RAISED BY PLASTIC DEFORMATION	787
GENERAL REFERENCES	788
SPECIFIC REFERENCES	789
12. Radial-Distribution Studies of Noncrystalline Materials	791
12-1 THEORY	793
12-2 EXPERIMENTAL REQUIREMENTS	797
12-3 CORRECTION AND SCALING OF EXPERIMENTAL INTENSITIES TO ABSOLUTE (ELECTRON) UNITS	799
12-3.1 Correction for Air Scatter,	799
12-3.2 Correction for Absorption by the Sample,	801
12-3.3 Correction for Polarization,	802
12-3.4 Correction for Incoherent Scattering,	802
12-4 UNIFIED DETERMINATION OF μT , $i(S)$, AND SCALING FACTOR K	804
12-5 REPRESENTATIVE EXPERIMENTAL PROCEDURE	806
12-6 SOURCES OF ERROR	816
12-6.1 Choice of Increment ΔS in the Computation of $\Sigma Si(S) \sin rS \Delta S$,	816
12-6.2 Scaling of the Experimental Intensity Curve; Absorption Corrections,	817
12-6.3 Discrete Errors in $Si(S)$; Termination-of-Series Errors,	819
12-7 SPECIFIC PROCEDURES FOR MINIMIZING ERRORS	823
12-7.1 Application of a Damping Factor,	823
12-7.2 Use of an Electronic Distribution Function,	824
12-7.3 General Procedure for Removing Spurious Features from the RDF,	826
12-7.4 Method for Correcting the RDF for Termination- of-Series Errors Only,	831
12-8 PRACTICAL EXAMPLES	833
12-8.1 Carbon Black,	833
12-8.2 Carbon Black: Unified Determination of μT , $i(S)$, and Scaling Factor K ,	835
12-8.3 Silica Glass,	837

12-8.4	Liquid Argon,	839
12-8.5	Vitreous Selenium,	840
12-8.6	Identification of Noncrystalline Patterns,	847
12-8.7	Other Representative Studies,	850
	<i>A. Liquid hydrocarbons,</i>	850
	<i>B. Binary alloys,</i>	850
	<i>C. Aggregates of oriented linear and planar molecules,</i>	851
	<i>D. Helical molecules in solution,</i>	851
	<i>E. Biological systems,</i>	851
	<i>F. Oriented systems,</i>	852
12-9	FURTHER REMARKS ON EXPERIMENTAL TECHNIQUES	852
12-10	CHARACTERIZATION OF ORDERING IN POLYMERS	854
	GENERAL REFERENCES	855
	SPECIFIC REFERENCES	856
Appendix I	Layout for a Diffraction Laboratory	861
Appendix II	The Handling and Processing of X-ray Film	867
Appendix III	Miscellaneous Constants and Numerical Data	872
Appendix IV	International Atomic Weights	873
Appendix V	Mass Absorption Coefficients μ/ρ of the Elements ($Z = 1$ to 83) for a Selection of Wavelengths	875
Appendix VI	Quadratic Forms for the Cubic System	878
Appendix VII	Atomic and Ionic Scattering Factors	880
Appendix VIII	Lorentz and Polarization Factors	892
Appendix IX	Temperature Factor Table	896
Appendix X	Warren's Powder Pattern Power Theorem	897
Author Index		901
Subject Index		923